Validation, Analysis and Evolution of Software Tests

Campobasso, Italy, March 20, 2018

(satellite workshop of SANER 2018)

IEEE proceedings together with SANER 2018 conference

Aims and Scope:

Software projects accumulate many test cases, encoding valuable expert knowledge about the software to the extent of many person years. Over time the reliability of the tests decreases and they become difficult to understand and maintain. Extra effort is required for repairing broken tests and adapting test suites and models to evolving software systems.

The International Workshop on Validation, Analysis, and Evolution of Software Tests (VST) brings together academics, industrial researchers, and practitioners for exchanging experiences, solutions and new ideas in applying methods, techniques and tools to advance the state of the art in test development and maintenance.

Topics include, but are not limited to:

- Test minimization and simplification
- Fault localization and automated repair
- Change analysis for software tests
- Test visualization and validation
- Documentation analysis
- Bug report analysis
- Test evolution
- Test case generation
- Model-based testing
- Combinations of the topics above

Submission:

Papers (up to five pages) are to be submitted in IEEE format.

All submissions must be original, unpublished, and not submitted concurrently for publication elsewhere. Paper submission is done via EasyChair: https://easychair.org/conferences/?conf=vst2018

Publication:

Accepted papers will appear in the proceedings of SANER 2018.

Important dates:

Abstract submission deadline: January 5, 2018
Full paper submission deadline: January 12, 2018
Notification of acceptance: February 9, 2018
Camera-ready version due: February 22, 2018
Workshop: March 20, 2018

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